

Docket No. 220033US2/atp



#5
31 May 02
R. Tall

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

IN RE APPLICATION OF: Fuyuhiko INOUE, et al.

SERIAL NO: 10/080,537

GAU: 2877

FILED: February 25, 2002

EXAMINER:

FOR: WAVEFRONT ABERRATION MEASURING METHOD AND UNIT, EXPOSURE APPARATUS, DEVICE
MANUFACTURING METHOD, AND DEVICE

INFORMATION DISCLOSURE/RELATED CASE STATEMENT UNDER 37 CFR 1.97

ASSISTANT COMMISSIONER FOR PATENTS
WASHINGTON, D.C. 20231

SIR:

Applicant(s) wish to disclose the following information.

REFERENCES

- ☒ The applicant(s) wish to make of record the references listed on the attached form PTO-1449. Copies of the listed references are attached, where required, as are either statements of relevancy or any readily available English translations of pertinent portions of any non-English language references.
- ☐ A check is attached in the amount required under 37 CFR §1.17(p).

RELATED CASES

- ☐ Attached is a list of applicant's pending application(s) or issued patent(s) which may be related to the present application. A copy of the patent(s), together with a copy of the claims and drawings of the pending application(s) is attached along with PTO 1449.
- ☐ A check is attached in the amount required under 37 CFR §1.17(p).

CERTIFICATION

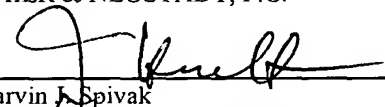
- ☐ Each item of information contained in this information disclosure statement was first cited in any communication from a foreign patent office in a counterpart foreign application not more than three months prior to the filing of this statement.
- ☐ No item of information contained in this information disclosure statement was cited in a communication from a foreign patent office in a counterpart foreign application or, to the knowledge of the undersigned, having made reasonable inquiry, was known to any individual designated in 37 CFR §1.56(c) more than three months prior to the filing of this statement.

DEPOSIT ACCOUNT

- ☒ Please charge any additional fees for the papers being filed herewith and for which no check is enclosed herewith, or credit any overpayment to deposit account number 15-0030. A duplicate copy of this sheet is enclosed.

Respectfully submitted,

OBLON, SPIVAK, McCLELLAND,
MAIER & NEUSTADT, P.C.


Marvin J. Spivak

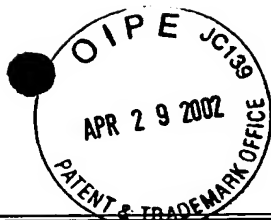
Registration No. 24,913

James D. Hamilton
Registration No. 28,421



22850

Tel. (703) 413-3000
Fax. (703) 413-2220
(OSMMN 10/98)



SHEET 1 OF 1

Form PTO 1449 (Modified)		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY DOCKET NO. 220033US2		SERIAL NO. 10/080,537	
LIST OF REFERENCES CITED BY APPLICANT				APPLICANT Fuyuhiko INOUE, et al.			
				FILING DATE February 25, 2002		GROUP 2877	
U.S. PATENT DOCUMENTS							
EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS	FILING DATE IF APPROPRIATE
	AA	4,490,039	12/25/84	J. M. BRUCKLER, et al.			
	AB	5,233,174	08/03/93	W. ZMEK			
	AC	6,130,419	10/10/2000	D. R. NEAL			
	AD	6,052,180	04/18/2000	D. R. NEAL			
	AE	5,936,720	08/10/99	D. R. NEAL, et al.			
	AF	6,184,974	02/06/2001	D. R. NEAL, et al.			
	AG	5,864,381	01/26/99	D. R. NEAL, et al.			
	AH	5,493,391	02/20/96	D. R. NEAL, et al.			
	AI	5,978,085	11/02/99	A. H. SMITH, et al.			
	AJ	5,828,455	10/27/98	A. H. SMITH, et al.			
	AK						
	AL						
	AM						
	AN						
FOREIGN PATENT DOCUMENTS							
		DOCUMENT NUMBER	DATE	COUNTRY	TRANSLATION YES NO		
	AO	1 079 223	02/28/2001	EUROPE			
	AP						
	AQ						
	AR						
	AS						
	AT						
	AU						
	AV						
OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, etc.)							
	AW	W. FREITAG, et al, JR, Insert, pages 8 -12, "WAVEFRONT ANALYSIS OF PHOTOLITHOGRAPHIC LENSES", January 1991					
	AX	T. NOGUCHI, et al., Publ. Natl. Astron. Obs. Japan, vol. 1, pages 49 - 55, "ACTIVE OPTICS EXPERIMENTS. 1." 1989					
	AY						
Examiner					Date Considered		
*Examiner: Initial if reference is considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.							